

Document description:

This document presents instance data illustrative of a functional specification as typically found in a data sheet for a component.

Page 2 provides the base product definition instance (#7) which includes two specification properties as examples { power and resistance} as well as the definition of terminals in the functional view. The names associated with e.g., #227 and #228 are signal names according to data sheet (e.g., in, out, gnd...) rather than pin numbers.

Reference other documents such as catalog data recommended practice for how to deal with tolerances, etc.

This page stands alone but there is no data provided to specify measurement setup.

Page 3 provides a testbench model (#117 and #115). #115 is a dummy set of data and IS NOT the base resistor model. It has to be populated to satisfy the standard. In some future edition we could relax the standard and get rid of it. #133 is the resistor function under test. #134 is an occurrence of some other function in the testbench. Not illustrated are voltage, current sources, etc....

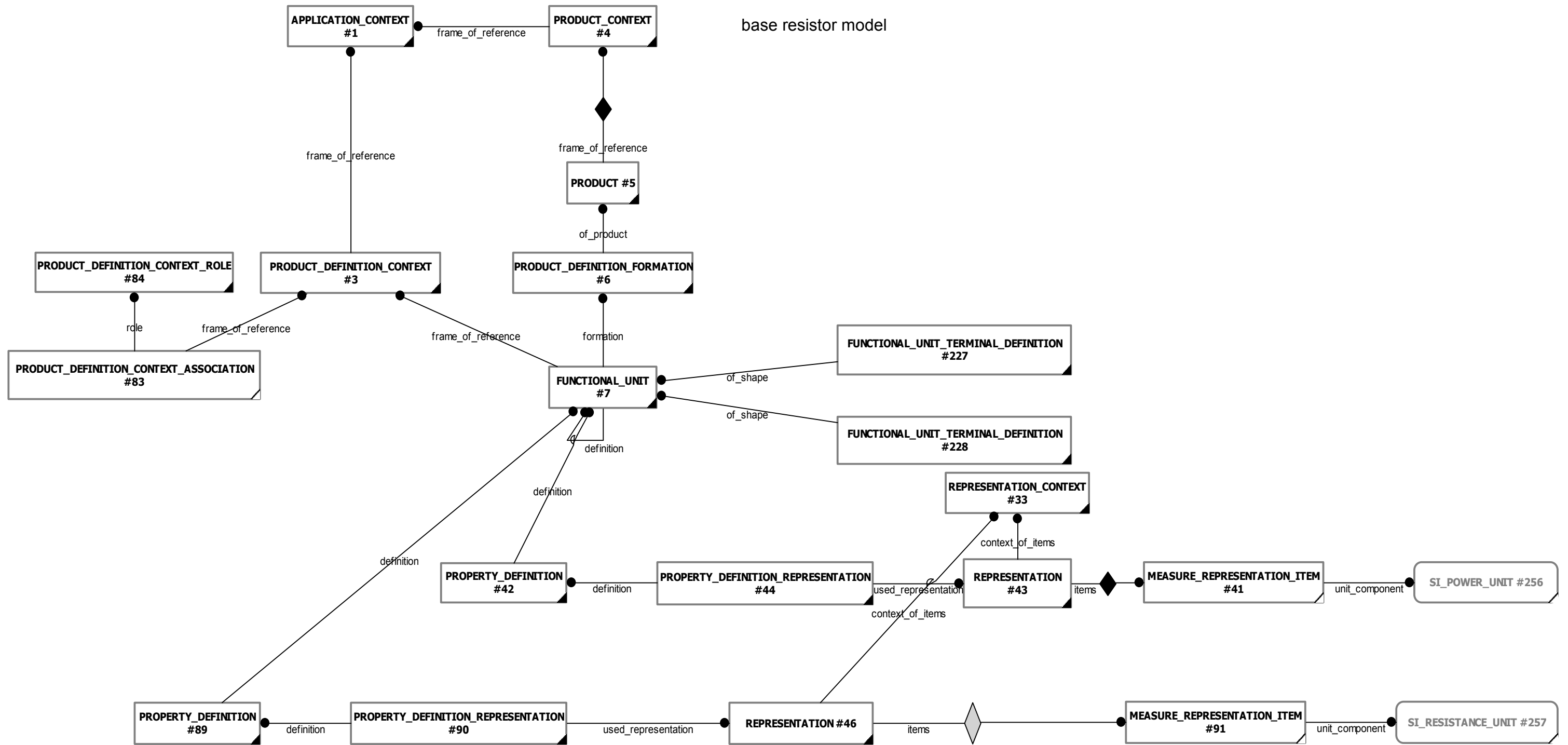
Page 4 provides instantiation data between terminals on the function definition (#227) and terminals on the occurrence (#234).

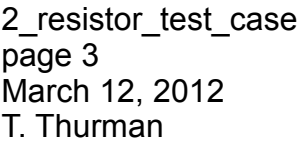
Also shown are two network nodes that also help to compose the testbench. Note that the two terminals on the occurrence are assigned to different nodes.

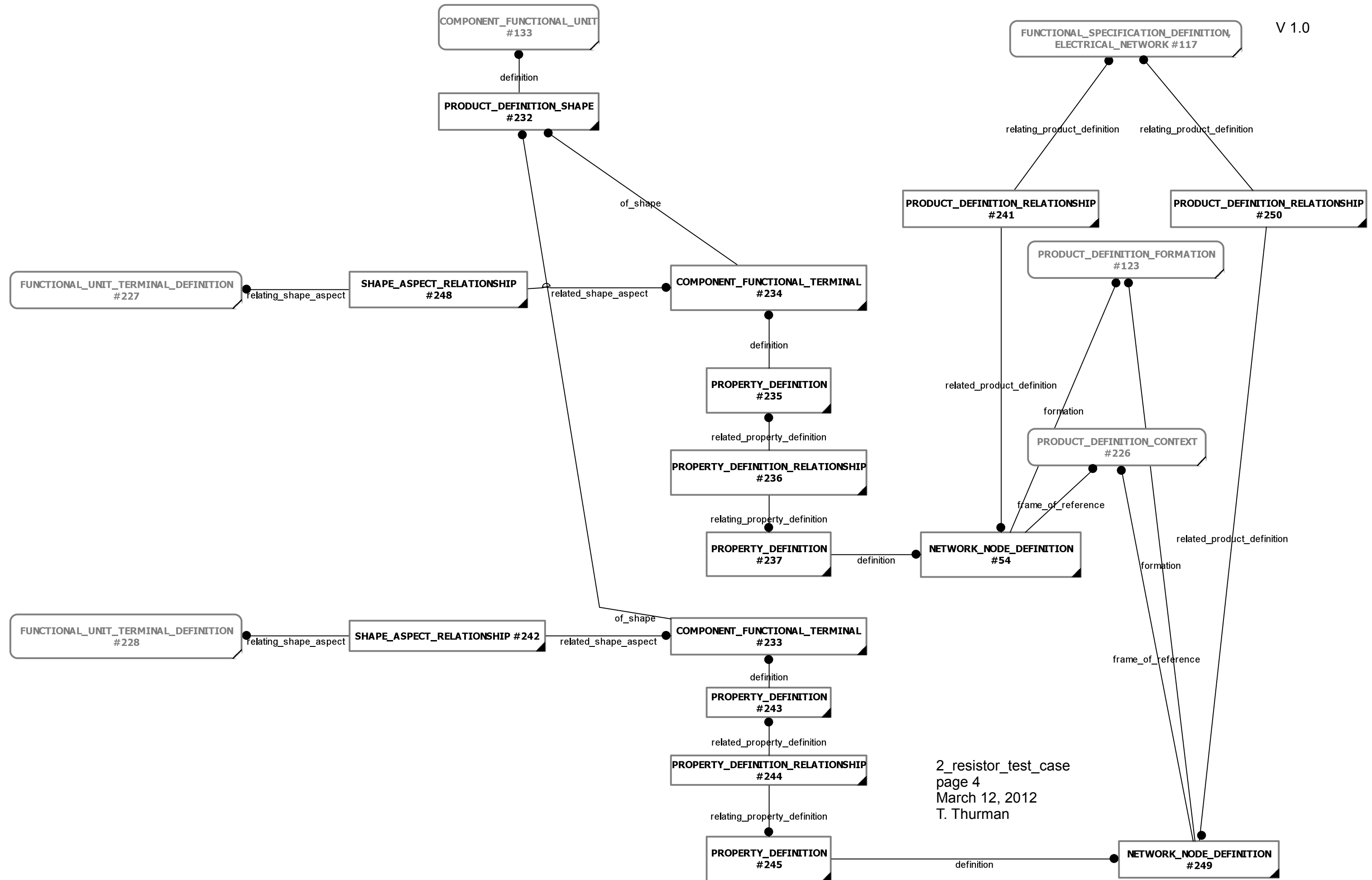
Page 5 provides an illustration of a functional specification (many may be associated with a testbench). In this case a signal #110 is to be defined between two terminals in the testbench (signal access mechanism in #100) and (signal reference mechanism in #104). The paths resolve to #235 and #245, respectively. (It is permissible to define signal access either to a node or to a terminal). Usually it is to a node as that is simpler, but there are cases where resolution is required to a terminal so the standard provides that support.

Page 6 illustrates how units should be composed. Since this recommended practice is relatively new, it is unlikely that any AP 210 files from Rockwell Collins will provide this structured data, but in the future we will see it in the MCAD data.

base resistor model







2_resistor_test_case
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March 12, 2012
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